

**Hex inverter****54F04****ORDERING INFORMATION**

DESCRIPTION	ORDER CODE	PACKAGE DESIGNATOR*
14-Pin Ceramic DIP	54F04/BCA	GDIP1-T14
14-Pin Ceramic Flat Pack	54F04/BDA	GDFP1-F14
20-Pin Ceramic LLCC	54F04/B2A	CQCC2-N20

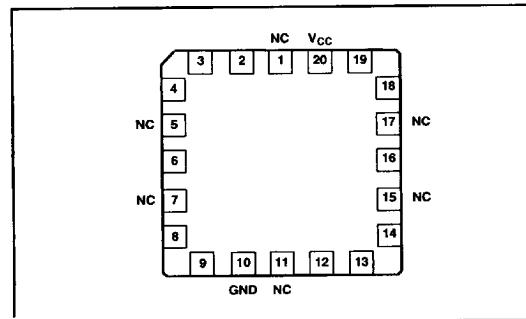
\* MIL-STD 1835 or Appendix A of 1995 Military Data Handbook

**ABSOLUTE MAXIMUM RATINGS**(Operation beyond the limits set forth in this table may impair the useful life of the device.  
Unless otherwise noted these limits are over the operating free-air temperature range.)

SYMBOL	PARAMETER	RATING	UNIT
V <sub>CC</sub>	Supply voltage range	-0.5 to +7.0	V
V <sub>I</sub>	Input voltage range	-0.5 to +7.0	V
I <sub>I</sub>	Input current range	-30 to +5	mA
V <sub>O</sub>	Voltage applied to output in High output state range	-0.5 to +V <sub>CC</sub>	V
I <sub>O</sub>	Current applied to output in Low output state	40	mA
T <sub>STG</sub>	Storage temperature range	-65 to +150	°C

**RECOMMENDED OPERATING CONDITIONS**

SYMBOL	PARAMETER	LIMITS			UNIT
		MIN	NOM	MAX	
V <sub>CC</sub>	Supply voltage	4.5	5.0	5.5	V
V <sub>IH</sub>	High-level input voltage	2.0			V
V <sub>IL</sub>	Low-level input voltage			0.8	V
I <sub>IK</sub>	Input clamp current			-18	mA
I <sub>OH</sub>	High-level output current			-1	mA
I <sub>OL</sub>	Low-level output current			20	mA
T <sub>A</sub>	Operating free-air temperature range	-55		+125	°C

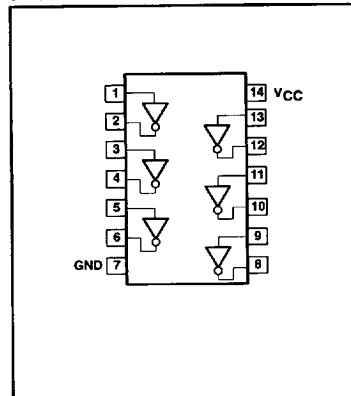
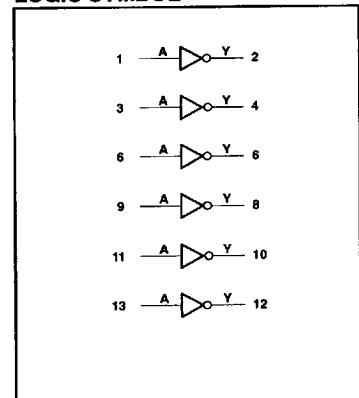
**LLCC LEAD CONFIGURATION**

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853-0225 F01024

**PIN CONFIGURATION****LOGIC SYMBOL**

## Hex inverter

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## INPUT AND OUTPUT LOADING AND FAN-OUT TABLE

PINS	DESCRIPTION	54F(U.L.) HIGH/LOW	LOAD VALUE HIGH/LOW
A	Inputs	1.0/1.0	20 $\mu$ A/0.6mA
Y	Outputs	50/33	1.0mA/20mA

NOTE: One (1.0) FAST Unit Load (U.L.) is defined as: 20 $\mu$ A in the High state and 0.6mA in the Low state.

## FUNCTION TABLE

INPUT	OUTPUT
A	Y
L H	H L

H = High voltage level

L = Low voltage level

## DC ELECTRICAL CHARACTERISTICS

(Over recommended operating free-air temperature unless otherwise noted.)

SYMBOL	PARAMETER	TEST CONDITIONS <sup>1</sup>			LIMITS			UNIT	
		MIN	TYP	MAX	MIN	TYP	MAX		
V <sub>OH</sub>	High-level output voltage	V <sub>CC</sub> = Min, V <sub>I</sub> = Max, I <sub>OH</sub> = Max, V <sub>IH</sub> = Min		2.5				V	
V <sub>OL</sub>	Low-level output voltage	V <sub>CC</sub> = Min, V <sub>I</sub> = Max, I <sub>OL</sub> = Max, V <sub>IH</sub> = Min			0.35	0.50		V	
V <sub>IK</sub>	Input clamp voltage	V <sub>CC</sub> = Min, I <sub>I</sub> = I <sub>IK</sub>			-0.73	-1.2		V	
I <sub>IH2</sub>	Input current at maximum input voltage	V <sub>CC</sub> = Max, V <sub>I</sub> = 7.0V					100	$\mu$ A	
I <sub>IH1</sub>	High-level input current	V <sub>CC</sub> = Max, V <sub>I</sub> = 2.7V					1	20	$\mu$ A
I <sub>IL</sub>	Low-level input current	V <sub>CC</sub> = Max, V <sub>I</sub> = 0.5V					-0.4	-0.6	mA
I <sub>OS</sub>	Short-circuit output current <sup>3</sup>	V <sub>CC</sub> = Max, V <sub>O</sub> = 0.0V			-60	-85	-150	mA	
I <sub>CC</sub>	Supply current (total)	I <sub>CCH</sub>	V <sub>CC</sub> = Max	V <sub>I</sub> = GND		2.8	4.2	mA	
		I <sub>CCL</sub>		V <sub>I</sub> ≥ 4.0V		10.2	15.3	mA	

## AC ELECTRICAL CHARACTERISTICS

SYMBOL	PARAMETER	TEST CONDITIONS	LIMITS					UNIT	
			T <sub>A</sub> = +25°C, V <sub>CC</sub> = +5.0V C <sub>L</sub> = 50pF R <sub>L</sub> = 500Ω		T <sub>A</sub> = -55°C to +125°C V <sub>CC</sub> = +5.0V ± 10% C <sub>L</sub> = 50pF, R <sub>L</sub> = 500Ω				
			MIN	TYP	MAX	MIN	MAX		
t <sub>PLH</sub> t <sub>PHL</sub>	Propagation delay A to Y	Waveform 1	2.4 1.5	3.7 3.2	5.0 4.3	1.5 1.1	7.0 6.5	ns ns	

## NOTES:

- For conditions shown as Min or Max, use the appropriate value specified under recommended operating conditions for the applicable type and function table for operating mode.
- All typical values are at V<sub>CC</sub> = 5V, T<sub>A</sub> = 25°C.
- Not more than one output should be shorted at a time. For testing I<sub>OS</sub>, the use of high-speed test apparatus and/or sample-and-hold techniques are preferable in order to minimize internal heating and more accurately reflect operational values. Otherwise, prolonged shorting of a High output may raise the chip temperature well above normal and thereby cause invalid readings in other parameter tests. In any sequence of parameter tests, I<sub>OS</sub> tests should be performed last.

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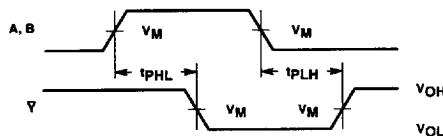
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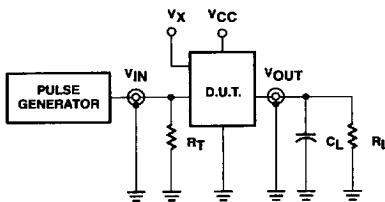
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## AC WAVEFORM

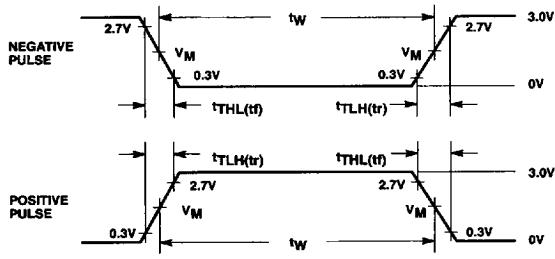


NOTE: For all waveforms,  $V_M = 1.5V$ .  
Waveform 1. For Inverting Outputs

## TEST CIRCUIT AND WAVEFORM



Test Circuit for Totem-Pole Outputs



Input Pulse Definition

## DEFINITIONS:

- $R_L$  = Load Resistor; see AC Characteristics for value.
- $C_L$  = Load capacitance includes jig and probe capacitance; see AC Characteristics for value.
- $R_T$  = Termination resistance should be equal to  $Z_{OUT}$  of pulse generators.
- $V_X$  = Unlocked pins must be held at:  $\leq 0.8V$ ;  $\geq 2.7V$  or open per FunctionTable.

INPUT PULSE CHARACTERISTICS				
Family	Rep. Rate	Pulse Width	$t_{TLH}$	$t_{THL}$
54F	1MHz	500ns	$\leq 2.5ns$	$\leq 2.5ns$

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